


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/698,712	YU ET AL.	
	Examiner	Art Unit	
	Christopher A. Revak	2131	

SEARCHED			
Class	Subclass	Date	Examiner
NONE	NONE	3/7/2006	CR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
713	168,176	11/14/2005	CR
382	181,190	11/14/2005	CR
382	191,232	11/14/2005	CR
380/200-203,205		11/14/2005	CR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
BRS Text Search USPAT, US PG PUB, USOCR, DERWENT, JPO, EPO, IBM TDB	3/7/2006	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	3/7/2006	CR

**Search Notes (continued)**

Application/Control No.

09/698,712

Examiner

Christopher A. Revak

Applicant(s)/Patent under  
Reexamination

YU ET AL.

Art Unit

2131

**SEARCHED**

Class	Subclass	Date	Examiner
NONE	NONE	3/7/2006	CR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
714	5,6,20	11/14/2005	CR
714	710,711	11/14/2005	CR
714	746,752	11/14/2005	CR
714/758,766,770,804		11/14/2005	CR

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
N/A		